Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination STAVELY ET AL. | Examiner | Art Unit | Page 1 of 1 | U.S. PATENT DOCUMENTS * | Document Number | Date | Country Code-Number-Kind Code | MM-YYYY | Name | Classification | Classification | Code | Country Code Number-Kind Code | Classification | Code | Country Code Number-Kind Code | Country Code Number-Kind Code | MM-YYYY | Name | Classification | Classification | Code | Country Code Number-Kind Code | Country Code Number-Kind Code | MM-YYYY | Name | Classification | Code | Country Code Number-Kind Code | Country Code Number-Kind Code | Country Code Number-Kind Code | Classification | Code | Country Code Number-Kind Code | Country Code Number-Kind Code | Classification | Code | Country Code Number-Kind Code | Classification | Classification | Classification | Code | Country Code Number-Kind Code | Classification | Cl

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